1. INTRODUCTION

This document specifies the necessary steps to execute a WARM SPIRE functional test during ILT test campaigns. It currently applies to the PFM model of SPIRE but it can be applied to further models as a minimum set of tests to verify the instrument correct functioning.

1.1 SCOPE

To judge the success or failure of a warm functional test by checking that:

- The telecommand sequence generated for a particular functional test is correctly received and executed on board by the SPIRE DPU.
- No error/event reports or command failures are generated during the execution of these commands.
- Telemetry is generated by the instrument as a result of telemetry requests to its different subunits.
- Particular telemetry parameters for each functional test change in an expected manner.
- A particular success criterion/criteria (specified in this document) is/are met.

1.2 REFERENCE DOCUMENTS

Ref	Document	Name	Version/Issue Nb.
RD01	SPIRE-RAL-DOC-001652	SPIRE Functional Tests Specification	Issue 1.4
RD02	SPIRE-RAL-DOC-001630	SPIRE EGSE-ILT Start-Up Procedures	Issue 0.7
RD03	SPIRE-RAL-PRC-002222	DRCU Switch ON Procedure	Issue 1.0
RD04	SPIRE-RAL-PRJ-001078	SPIRE Data ICD	Issue 2.0
RD05	Sap-SPIRE-CCa-076-02	DRCU/DPU Interface Control Document	Issue 1.2
RD06	LAM.PJT.SPI.NOT.011011	MCU/DPU Command List ICD	Issue 5.0
RD07	SPIRE-IFS-PRJ-001391	SPIRE OBS User Manual	Issue 2.1

1.3 CHANGE RECORD

Document	Change date	Changes
Draft 1	15/12/04	First Draft.
Draft 2	04/08/05	Second Draft. Updated first draft according to latest changes introduced in RD04 to calibration curves. Included a general test sequence layout, missing before.
Issue 1.0	11/08/05	Replaced FUNC-DCU-04P/S in second draft for FUNC-DCU-11P/S to switch ON detectors for later load curve. Included actual load curves for photometer and spectrometer FUNC-DCU-13P and FUNC-DCU-13/S.
Issue 1.1	24/11/05	Changes on the overall functional test sequence following discussion. Changes to the workstation names after the hardware update. Swapped sections 2.1 with 2.2. Replaced section 2.3 (should be noted in another document) for an initial instrument configuration check. Removed section 4.1 Test Log
Issue 1.2	27/02/06	General document layout modification

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2. FUNCTIONAL TEST CONFIGURATION

2.1 Software Configuration

Annotate in the table the current EGSE software configuration for the tests:

EGSE component	Version/Build number	Comment
SCOS2000		
HCSS		
QLA		
QLA scripts		
Test Control scripts		
CUS Scripts		

2.2 EGSE Configuration Checks

To check for the success of failure of a functional test, the real time telemetry of the instrument has to be monitored. The following applications must be running to do so. Before the test sequence starts, make the following checks:

Workstation	EGSE component	Status	Check
Lichfield	EGSE router	Started	
Lichfield	EGSE Gateway	Started	
Lichfield	Telemetry Ingestion	Started	
Lichfield	Packet Display	Started	
Lincoln	SCOS2000	Started	
Lincoln	EXIF + TOPE	Started	
Lincoln	Manual Stack	Started	
Gordon	CDMS Simulator	Started	
Lincoln	Test Control Server	Started	

2.3 SPIRE Instrument Configuration

The functional test flow is such that at a given time during the procedure is possible that the instrument configuration does not conform to any nominal configuration as specified in Annexe 1. Nevertheless the configuration prior and after a test is specified for each functional test, and were applicable and the instrument configuration is in accordance to Anexe1, this will be denoted by showing the main configuration in blue bold font and any additional subsystems configuration in black.
The **initial** instrument configuration for WFT does conform to a 'known' configuration and should be SPIRE **DRCU_ON**.
Perform the following actions to ensure that the instrument is in the correct configuration for the tests.

Step#	Action	Comments	Check
1	In SCOS open **DPU_AND_OBS_PARAMETERS display** Check if : TM2N is incrementing by one @1Hz. TM1N is incrementing by one @0.5Hz. - If they are, go to step 5. - If they are not, go to step 2.	**In SCOS Main Window start either MON1 or MON2 tasks.**	
2	Check if the DPU is powered ON: - If ON, the DPU power supply LCD will show ~ 28V and 0.40A, go to step 4. - If not ON, power ON DPU see comments on the right, then go to step 3.	**To power ON the DPU press the main switch on the front bottom left of the DPU power supply, wait for the LCD display to show 28 V reading and then press the secondary switch on the front bottom right labelled *Input 1*.**	
3	In SCOS open **Boot_ROM_Memory_Check display** and check no errors are reported: - If no errors are reported, execute DPU_ON from HCSS Test Procedures. Then repeat step 1. - If the (5,2) contains errors: Check the error code in RD07. Then switch OFF the DPU and repeat step 2	**As soon as DPU is powered ON, the boot software performs some internal checks and generates:** • **A (5, 2) event TM packet for DPU models previous to CFM model** • **A (5,1) event for the CFM model and further ones** **This packet contains the number of errors at check time.**	
4	Execute **define_new_HK_report.tcl** HCSS Test procedure. Repeat step 1.		
5	In SCOS open **SCU_PARAMETERS display** - If SCUP5V/P9V/M9V are jittering and **BIAS_PARAMETERS display** - If BIAS1TEMP,BIAS2TEMP,… show ambient temperature, the DRCU is ON.Go to step 6. - If DRCU is not ON, refer to RD03 on how to start up the DRCU.		
6	**In SCOS open** DPU_AND_OBS_PARAMETERS display **and check that the MODE housekeeping parameter is DRCU_ON.**	**MODE (RAW)= 0x100** **MODE (ENG) = DRCU_ON**	

Table 1. Initial configuration check

3. TEST PROCEDURE

The following two sections describe general pass/fail criteria (Section 3.1), the general test procedure layout (Section 3.1) and the detailed procedure for each functional test (Section 3.2).

3.1 GENERAL PASS/FAIL CRITERIA

The general criterion for declaring a single test failed is the repeated failure of 2 consecutive runs of this test. In that case the functional test procedure should be aborted and the overall functional testing declared FAILED.
In the case of a 'first run' failure followed by a successful execution a third run of the same test should be performed and in the unlikely event of this third run being a failure the test procedure should be also aborted and the overall functional testing declared FAILED, as this would imply a not reliable operability of the instrument.
As a general remark ANY failure should be closely analyzed.

Note: If the functional test is declared FAILED refer to section 4.1 for instrument switch OFF.

3.2 GENERAL TEST PROCEDURE LAYOUT

The table below shows the general WFT sequence as it should be performed. In each step of this procedure the operator should refer to the detailed procedure in Section 3.2 .Test Control TCL scripts are available to invoke the correspondent CUS script stored in the HCSS database for each functional test. These CUS scripts will generate the appropriate command sequence for the particular functional test.

Step	Subsystem tested	Test Id	Test Purpose
1	SCU	FUNC-SCU-01	SCU Nominal Science Generation Check
2		FUNC-SCU-03	FPU DC Thermometry Check
3		FUNC-SCU-06	FPU AC Thermometry Check
4		FUNC-SCU-02	SCU Nominal Science Contents Check
5		FUNC-SCU-08	SCU Test Pattern Check
6		FUNC-SCU-07	Sorption Cooler Check
7		FUNC-SCU-04	Photometer Calibrator Check
8		FUNC-SCU-05	Spectrometer Calibrators Check
9	MCU	FUNC-MCU-01	MCU Boot Check
10		FUNC-MCU-02	MCU Nominal Science Generation Check
11		FUNC-MCU-03	MCU Nominal Science Contents Check
12		FUNC-MCU-04	MCU Test Pattern Check
13	BSMm	FUNC-BSM-01	BSM Switch ON Check
14		FUNC-BSM-02c	BSM Chop Sensor Polarity Check
15		FUNC-BSM-02j	BSM Jiggle Sensor Polarity Check
16		FUNC-BSM-03	BSM Open Loop dynamics Check
17		BSM_INIT*	Close loop on chop/jiggle axis.
18		FUNC-BSM-06	BSM Operational Mode Check
18	SMECm	FUNC-SMEC-02A/B*	SMEC Launch Latch Open/Close Check
19		FUNC-SMEC-01	SMECm Switch ON Check

20		**FUNC-SMEC-03**	SMEC LED Optical Encoder LED Check
21		**FUNC-SMEC-04**	SMEC Positioning Test (Open Loop)
22	**DCU**	**FUNC-DCU-01**	DCU Nominal Science Generation Check
23		**FUNC-DCU-02**	DCU Nominal Science Contents Check
24		**FUNC-DCU-03**	DCU Test Pattern Check
25	**Photometer LIAs**	**FUNC-DCU-04P**	Photometer LIAs Check
26		**FUNC-DCU-05P**	Photometer Manual Offset Setting Check
27		**FUNC-DCU-11P**	Photometer Detectors Switch ON Check
28	**Photometer BDAs**	**FUNC-DCU-013P**	Photometer Detectors Check
29	**Spectrometer LIAs**	**FUNC-DCU-04S**	Spectrometer LIAs Check
30		**FUNC-DCU-05S**	Spectrometer Manual Offset Setting Check
31		**FUNC-DCU-11S**	Spectrometer Detectors Switch ON Check
32	**Spectrometer BDAs**	**FUNC-DCU-013S**	Spectrometer Detectors Check

Table 2. General WFT sequence

***Note**: If the procedure is executed prior to an FPU cooldown FUNC-SMEC-02A should be executed. If the procedure is executed after an FPU warm up FUNC-SMEC-02B should be executed.

***Note:** This procedure is not a functional test, is a close loop initialisation procedure required to test the close loop operability of the BSM.

3.3 DETAILED TEST PROCEDURE

The following is a detailed (test by test) procedure including the steps required to perform each functional test individually.

Step#	Action	Comments
0	Open **SCU_PARAMETERS** display on SCOS Alpha Numeric Displays.	

3.3.1 FUNC-SCU-01

Test Id:	**FUNC-SCU-01**
Initial Configuration:	**DRCU_ON**
Final Configuration:	**DRCU_ON**
Success Criteria:	Test passed if : 1. Two SCU Nominal Science Report telemetry packets are received on QLA with the following characteristics:

APID	Type	Subtype	SID	FrameID	Frame length
0x508	21	1	0xA20	0x20	0x1E

2. The frame time difference between consecutive SCU frames within these packets corresponds to the sampling rate. Nominal SCU sampling rate is 80Hz ➔ $\Delta t = 12.5$ ms
3. The SPIRE HK parameter SCUFRAMECNT increments by 31.
4. No events are generated during the frame generation.

	QLA to give go ahead.

Test Procedure:

Step#	Action	Comments
1	Annotate the initial value of SCUFRAMECNT parameter located in SCU_PARAMETERS display.	
2	Run QLA script FUNC-SCU-01.py on QLA console.	
3	Run FUNC-SCU-01 test procedure from the HCSS Test Procedure window on TOPE	
4	Annotate the final value of SCUFRAMECNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-01	**SCUFRAMECNT**	**n/ n+ 31**			

Start time @:
End time @:
OBSID:
Comments:

3.3.2 FUNC-SCU-03

Test Id:	FUNC-SCU-03
Initial Configuration:	DRCU_ON
Final Configuration:	DRCU_ON + DC thermometry ON
Success Criteria:	Test passed if all FPU DC thermometry sensors show temperature values indicating a correct functioning of the sensor, not open/short-circuited. If ANY reading is anomalous check RAW sensor reading. **Open Circuit Criterion:** **RAW reading in the range [0, -100]** **Short Circuit Criterion:** **RAW reading of -32768** **Note:** For some parameters the calibration curve above 75K has only 2 points, thus the linearly interpolated temperature reading given by SCOS is usually not correct at T > 75K.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-SCU-03 test procedure from the HCSS Test Procedure window on TOPE	
2	When the test is finished annotate the current value of SCUTEMPSTAT and the RAW/converted values of the 16 FPU temperatures located in SCU_PARAMETERS display.	
3	Contingency: If test fails execute SCU_OFF procedure from HCSS Test Procedure window on TOPE and then repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-03	**SCUTEMPSTAT**	**0/0xFFFF**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.3 FUNC-SCU-06

Test Id:	FUNC-SCU-06
Initial Configuration:	DRCU_ON + DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if SUBKSTAT parameter went from 0 to 1. **Open Circuit Criterion:** **RAW reading in the range 0 -100** **Short Circuit Criterion:** **RAW reading of -32768**

Test Procedure:

Step#	Action	Comments
1	Run FUNC-SCU-06 test procedure from the HCSS Test Procedure window on TOPE.	
2	When the test is finished annotate the current value of SUBKSTAT located in SCU_PARAMETERS display. Also write down the RAW value of the SUBKTEMP parameter.	
3	Contingency: If test fails : 1. Send manual command: SEND_DRCU_COMMAND Parameter1 = 0xA0860000 Parameter2 = 0 2. Then repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-06	**SUBKSTAT**	**0/1**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.4 FUNC-SCU-02

Test Id:	FUNC-SCU-02
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON
Success Criteria:	Test passed if : 1. Parameters in the SCU Nominal science packets and the same parameters in the Nominal HK packet have similar RAW/converted values to within 10%. 2. The SPIRE HK parameter SCUFRAMECNT located in **SCU_PARAMETERS** display increments by 31. 3. No events are generated during the frame generation. QLA to give the go ahead.

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of SCUFRAMECNT located in SCU_PARAMETERS display.	
2	Run QLA script FUNC-SCU-02.py on QLA console.	
3	Run FUNC-SCU-02 test procedure from the HCSS Test Procedure window on TOPE	
4	When the test is finished annotate the current value of SCUFRAMCNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-02	**SCUFRAMECNT**	**n+31/n+62**			

Start time @:
End time @:
OBSID:
Commets:

3.3.5 FUNC-SCU-08

Test Id:	FUNC-SCU-08
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if : 1. Two SCU Diagnostic Science Report telemetry packets are received with the following characteristics: 2. The SCU Test Pattern agrees with the reference test pattern. QLA to give go ahead.

APID	Type	Subtype	SID	FrameID	Frame length
0x508	21	3	0x1120	0x21	0x1E

Test Procedure:

Step#	Action	Comments
1	Annotate the current values of SCUFRAMECNT located in SCU_PARAMETERS display.	
2	Run QLA script FUNC-SCU-08.py on QLA console.	
3	Run FUNC-SCU-08 test procedure from the HCSS Test Procedure window on TOPE	
4	When the test is finished annotate the current value of SCUFRAMCNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-08	**SCUFRAMECNT and SCU test pattern frame parameters**	**n+62/n+93**			

Start time @:
End time @:
OBSID:
Commets:

3.3.6 FUNC-SCU-04

Test Id:	FUNC-SCU-04
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON
Success Criteria:	Test passed if PCALCURR/PCALV SCU HK parameters show the following values: • PCALCURR HK parameter which shows the measured PCAL current is ~ 0.1 mA. • PCALV HK parameter which shows the measured PCAL voltage is ~ 0.02V

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of PCALV and PCALCURR located in SCU_PARAMETERS display.	
2	Run FUNC-SCU-04 test procedure from the HCSS Test Procedure window on TOPE	
3	While the test is running Annotate the values of PCALV and PCALCURR.	
4	Contingency: If test fails repeat steps 1 to 3.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/During test	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-04	**PCALCURR** **PCALV**	**0/0.1mA** **0/0.02V**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.7 FUNC-SCU-05

Test Id:	FUNC-SCU-05
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if : • SCAL2CURR ,SCAL4CURR HK parameters which show the measured current read ~ 0.1 mA • SCAL2V,SCAL4V parameters which show the measured voltage read ~ 0.05V.

Test Procedure

Step#	Action	Comments
1	Annotate the current value of SCAL2V ,SCAL2CURR,SCAL4V,SCAL4CURR located in SCU_PARAMETERS display.	
2	Run FUNC-SCU-05 test procedure from the HCSS Test Procedure window on TOPE	
3	While the test is running write the values of SCAL2V ,SCAL2CURR,SCAL4V,SCAL4CURR.	
4	Contingency: If test fails repeat steps 1 to 3.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/During test	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-05	**SCAL2CURR** **SCAL2V** **SCAL4CURR** **SCAL4V**	**0/0.1mA** **0/0.05V** **0/0.1mA** **0/0.05V**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.8 FUNC-SCU-07

Test Id:	FUNC-SCU-07
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if during the execution of the test the following SCU HK parameters give correspondent readings of:

SCU HK parameter	RAW	Converted
SPHSV	**~12715**	**~323mV**
EVHSV	**~12715**	**~323mV**
SPHTRV	**~14390**	**~ 8 V**

Test Procedure:

Step#	Action	Comments
1	Run FUNC-SCU-07 test procedure from the HCSS Test Procedure window on TOPE.	
2	While the test is running annotate the values of current values of SPHSV, EVHSV, SPHTRV located in SCU_PARAMETERS display. (RAW and CONVERTED)	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/During test	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-07	**SPHSV** **EVHSV** **SPHTRV**	**0/ ~ 323 mV** **0/ ~ 323 mV** **0/ ~ 8 V**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

Step#	Action	Comments
0	Open **MCU_PARAMETERS** display on SCOS Alpha Numeric Displays.	

3.3.9 FUNC-MCU-01

Test Id:	**FUNC-MCU-01**
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON
Success Criteria:	Test passed if: 1. MCU boots. 2. MCU voltages show expected values. 3. MAC Board Temperature Reading shows ambient temperature.

Test Procedure:

Step#	Action	Comments
1	Run **FUNC-MCU-01** test procedure from the HCSS Test Procedure window on TOPE	
2	When procedure is finished Annotate the values of the MCU voltages.	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-01	**MCUP5V** **MCUP15V** **MCUP14V** **MCUM14V** **MCUM15V** **MCUMACTEMP**	**N/A/ ~ 5V** **N/A / ~15V** **N/A / ~ 14V** **N/A / ~ -14V** **N/A / ~ -15V** **N/A / ~ 300K**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.10 FUNC-MCU-02

Test Id:	FUNC-MCU-02
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Success Criteria:	Test passed if : 1. MCU produces each type of the frames requested and with the following characteristics.

Frame	APID	Type	Subtype	SID	FrameID	Frame length
Eng.	**0x508**	**21**	**3**	**0x814**	**0x14**	**0x15**
BSM	**0x508**	**21**	**1**	**0x612**	**0x12**	**0xD**
SMEC	**0x508**	**21**	**1**	**0x410**	**0x10**	**0xC**
BSM +SMEC						

2. No events are generated during the different frames generation.

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of MCUFRAMECNT located in MCU_PARAMETERS display	
2	Run QLA script FUNC-MCU-02.py on QLA console.	
3	Run FUNC-MCU-02 test procedure from the HCSS Test Procedure window on TOPE	
4	When test is finished annotate the current value of MCUFRAMECNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-02	**MCUFRAMECNT**	**0/ ~ 3300**			

Start time @:
End time @:
OBSID:
Commets:

3.3.11 FUNC-MCU-03

Test Id:	FUNC-MCU-03
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Success Criteria:	Test passed if : 1. MCU produces 100 frames of each type of frames requested with the following characteristics:

Frame	APID	Type	Subtype	SID	FrameID	Frame length
Eng.	**0x508**	**21**	**3**	**0x814**	**0x14**	**0x15**
BSM	**0x508**	**21**	**1**	**0x612**	**0x12**	**0xD**
SMEC	**0x508**	**21**	**1**	**0x410**	**0x10**	**0xC**
BSM +SMEC						

2. No events are generated during the different frames generation.
3. QLA analysis results are correct.(FIXME)

QLA to give go ahead.

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of MCUFRAMECNT located MCU_PARAMETERS display.	
2	Run QLA script FUNC-MCU-03.py on QLA console.	
3	Run FUNC-MCU-03 test procedure from the HCSS Test Procedure window on TOPE	
4	When test is finished annotate the current value of MCUFRAMECNT	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-03	**MCUFRAMECNT**	**n/ n+300** **n~3300**			

Start time @:
End time @:
OBSID:
Commets:

3.3.12 FUNC-MCU-04

Test Id:	FUNC-MCU-04
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Success Criteria:	Test passed if: 1. MCU produces 100 frames of Test Pattern with the following characteristics: 2. MCU Test pattern produced is the same as the previous time this test was run. QLA to give go ahead.

Frame	APID	Type	Subtype	SID	FrameID	Frame length
Test	**0x508**	**21**	**3**	**0x915**	**0x15**	**0x15**

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of MCUFRAMECNT located in MCU_PARAMETERS display.	
2	Run QLA script FUNC-MCU-04.py on QLA console.	
3	On Lincoln run FUNC-MCU-04 test procedure from the HCSS Test Procedure window on TOPE	
4	When test is finished annotate the current value of MCUFRAMECNT	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-04	**MCUFRAMECNT**	**m/ m+100 m~3600**			

Start time @:
End time @:
OBSID:
Commets:

Step#	Action	Comments
0	Open **CHOP PARAMETERS display** on SCOS Alpha Numeric Displays.	

3.3.13 FUNC-BSM-01

Test Id:	**FUNC-BSM-01**
Initial Configuration:	**DRCU_ON +** AC/DC thermometry ON +MCU ON
Final Configuration:	**DRCU_ON +** AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if: 1. CHOPSENSPWR HK parameter goes from 0 to 1 2. CHOPDACVAL HK parameter goes from 0 to 0x8000 3. CHOPSENSIG HK parameter shows variation from off to on 4. JIGGSENSPWR HK parameter goes from 0 to 1 5. JIGGDACVAL parameter goes from 0 to 0x8000 6. JIGGSENSSIG HK parameter shows variation from off to on

Test Procedure

Step#	Action	Comments
1	On QLA bring up a time series display of the following HK parameters: CHOPSENSPWR CHOPDACVAL CHOPSENSIG JIGGSENSPWR JIGGDACVAL JIGGSENSSIG	
2	Run FUNC-BSM-01 test procedure from the HCSS Test Procedure window on TOPE	
3	When the test is finished record all the Key parameters noted bellow	
	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-01	**CHOPSENSPWR** **CHOPLOOPMODE** **CHOPDACVAL** **CHOPFFGAIN** **CHOPSENSSIG** **JIGGSENSPWR** **JIGGLOOPMODE** **JIGGDACVAL** **JIGGFFGAIN** **JIGGSENSSIG**	**0/1** **0/3** **0/0x8000** **0/0xBEB** **0/?** **0/1** **0/3** **0/0x8000** **0/0xBEB** **0/?**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.14 FUNC-BSM-02c

Test Id:	FUNC-BSM-02c
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if the chop sensor signal evolves in the same way as the positions set.(i.e if (pos1 > pos2 ➔ sig1 > sig2)

Test Procedure:

Step#	Action	Comments
1	On QLA open up a time series display of HK parameter CHOPDACVAL and CHOPSENSSIG	
2	Run FUNC-BSM-02c test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-02c	CHOPDACVAL CHOPSENSSIG			N/A	

Start time @:
End time @:
OBSID:
Commets:

3.3.15 FUNC-BSM-02j

Test Id:	FUNC-BSM-02j
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if the jiggle sensor signal evolves in the same way as the positions set.(i.e if (pos1 > pos2 ➔ sig1 > sig2)

Test Procedure:

Step#	Action	Comments
1	On QLA open up a time series display of HK parameter JIGGDACVAL and JIGGSENSSIG	
2	Run FUNC-BSM-02j test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-02j	**JIGGDACVAL** **JIGGSENSSIG**			**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.16 FUNC-BSM-03

Test Id:	FUNC-BSM-03
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if the chop sensor signal evolves in the same way as the positions set.(i.e if (pos1 > pos2 ➔ sig1 > sig2) for each jiggle position. **Note:** During warm tests the voltages on both chop and jiggle motors are likely to be saturated (CHOP/JIGGMOTORVOLT RAW values of ~ 0xFFFF) due to the high resistance of the motor coil at ambient temperature.

Test Procedure

Step#	Action	Comments
1	On QLA open up a time series display of HK parameters: CHOPPOSN CHOPDACVAL CHOPMOTORCURR CHOPSENSSIG CHOPMOTORBEMF JIGGPOSN JIGGDACVAL JIGGMOTORCURR JIGGSENSSIG JIGGMOTORBEMF	
2	Run FUNC-BSM-03 test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat step 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-03				**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.17 FUNC-BSM-06

Step#	Action	Comments
0	Execute BSM_INIT from HCSS Test Procedures	

Test Id:	**FUNC-BSM-06**
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	**Note:** **The purpose of this test is to check the effectiveness of the BSM close loop initialisation procedure and the default PID parameters.** **If the dynamical behaviour of the BSM during chopping with these PID parameters is close or within requirements this indicates that the PID parameters used can be applied to cold testing with certain adjustment.** **If NOT these indicates that the PID parameters need further tuning BUT NOT TO BE DONE DURING THESE TEST.** **In any case the success/fail criteria are NOT applicable for this test.**

Test Procedure

Step#	Action	Comments
1	On QLA open up a time series display of HK parameters: CHOPDACVAL CHOPMOTORCURR CHOPSENSSIG	
2	Run FUNC-BSM-06 test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: None contemplated.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-06	**CHOPSENSSIG** **CHOPMOTORCURR** **CHOPDACVAL**	**?/?** **?/?** **?/?**		**N/A**	**N/A**
Start time @: **End time @:** **OBSID:** **Commets:**					

Step#	Action	Comments
4	Execute BSM_OFF from HCSS Test Procedures	

Step#	Action	Comments
0	Open **SMEC PARAMETERS display** on SCOS Alpha Numeric Displays.	

3.3.18 FUNC-SMEC-02A/B

Test Id:	**FUNC-SMEC-02A/B**
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON +MCU ON + SMEC ON **If WFT prior to cooldown** : Smec Latched **If WFT after warm up** : Smec Unlatched
Final Configuration:	**DRCU_ON +** AC/DC thermometry ON +MCU ON + SMEC ON **If WFT prior to cooldown** : Smec Unlatched **If WFT after warm up** : Smec Latched
Success Criteria:	Test passed if : Prior to un-latching the resistance across pins 7 and 8 of the launch latch is ~ 368 Ohms. After un-latching the resistance is 483 Ohms. **Note:** These resistance values were recorded for the CQM SMEC model, for the flight SMEC, these values are expected to vary.

Step#	Action	Comments
1	Measure the resistance across pins 7 and 8 of the launch latch.	
2	If WFT prior to cooldown: Run FUNC-SMEC-02A test procedure from the HCSS Test Procedure window on TOPE If WFT after warm up: Run FUNC-SMEC-02B test procedure from the HCSS Test Procedure window on TOPE	
3	Measure the resistance across pins 7 and 8 of the launch latch.	
4	Contingency: If test fails repeat steps 1.	

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-02A/B				**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.19 FUNC-SMEC-01

Test Id:	FUNC-SMEC-01
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if : 1. SMECENCPWR HK parameter changes from 0 to 6. 2. SMEC encoder signals 1 and 2 amplitude show variation when encoder is switched ON. 3. SMEC LVDT is switched ON. 4. SMEC LVDT DC and AC signals show variation when LVDT is switched ON.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a display of the following HK parameters: SMECENCPWR SMECENCSIG1AMP SMECENCSIG2AMP SMECLVDTDCSIG SMECLVDTACSIG	
2	Run FUNC-SMEC-01 test procedure from the HCSS Test Procedure window on TOPE	
	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-01	**SMECENCPWR SMECLVDTPWR SMECENCSIG1 SMECENCSIG2**			**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.20 FUNC-SMEC-03

Test Id:	FUNC-SMEC-03
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if: SMEC encoder signals 1 and 2 show a variation on their amplitudes from one LED illumination level to another.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the following Nominal HK parameters: SMECENCSIGAMP1 SMECENCSIGAMP2	
2	Run FUNC-SMEC-03 test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-03	SMECENCPWR SMECENCSIG1AMP SMECENCSIG2AMP				

Start time @:
End time @:
OBSID:
Commets:

3.3.21 FUNC-SMEC-04a

Test Id:	FUNC-SMEC-04a
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop)
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if SMECLVDTDCSIG parameter shows a variation according to the different positions set.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the following Nominal HK parameters: SMECENCSIG1 SMECENCSIG2 SMECLVDTDCSIG SMECLVDTACSIG SMECMOTORCURR	
2	Run FUNC-SMEC-04a test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-04a	**SMECLVDTDCSIG**				

Start time @:
End time @:
OBSID:
Commets:

Step#	Action	Comments
4	Execute SMEC_OFF from HCSS Test Procedures	

Step#	Action	Comments
0	Open **DCU PARAMETERS** SCOS Alpha Numeric Display	

3.3.22 FUNC-DCU-01

Test Id:	**FUNC-DCU-01**
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON
Success Criteria:	Test passed if: 1. DCU produces each type of DCU nominal science frame with the following characteristics.

APID	Type	S.type	SID	Frame ID	Frame type	Nb. Of frames	Nb. of pkts.
0x504	**21**	**1**	**0x200**	**0**	**PF**	**100**	**100**
0x506	**21**	**1**	**0x201**	**1**	**SF**	**100**	**17**
0x504	**21**	**2**	**0x102**	**2**	**PSW**	**100**	**34**
0x504	**21**	**2**	**0x103**	**3**	**PMW**	**100**	**25**
0x504	**21**	**2**	**0x104**	**4**	**PLW**	**100**	**12**
0x506	**21**	**2**	**0x105**	**5**	**SSW**	**100**	**12**
0x506	**21**	**2**	**0x106**	**6**	**SLW**	**100**	**7**

2. The frame time difference between consecutive DCU frames of each type corresponds to the sampling rate.
   Photometer Sampling rate is 15.3Hz → $\Delta t \sim 65.5$ ms
   Spectrometer Sampling rate is 80Hz → $\Delta t = 12.5$ ms
3. The SPIRE HK parameter DCUFRAMECNT increments by 700.
4. No events are generated during the frames generation.

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
2	Run FUNC-DCU-01 test procedure from the HCSS Test Procedure window on TOPE	
3	Annotate the current value of DCUFRAMECNT located d in DCU	

	PARAMETERS AND	
4	Contingency: If test fails repeat steps 1 to 3.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-01	**DCUFRAMECNT**	**0/700**			

Start time @:
End time @:
OBSID:
Commets:

3.3.23 FUNC-DCU-02

Test Id:	**FUNC-DCU-02**
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON
Success Criteria:	Test passed if DCUFRAMECNT goes from 700 to 1400 and the frametime difference between consecutive frames computed by QLA script is in agreement with the expected differences based on commanded sampling rate: 1. Photometer Sampling rate is 15.3Hz → Δt ~ 65.5 ms 2. Spectrometer Sampling rate is 80Hz → Δt = 12.5 ms

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
2	Run QLA script FUNC-DCU-02.py on QLA console.	
3	Run FUNC-DCU-02 test procedure from the HCSS Test Procedure window on TOPE	
4	Annotate the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-02	**DCUFRAMECNT**	**700/1400**			

Start time @:
End time @:
OBSID:
Commets:

3.3.24 FUNC-DCU-03

Test Id:	FUNC-DCU-03
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Success Criteria:	Test passed if : 1. DCU produces 100 frames of Full Photometer Test Pattern and 100 frame of Full Spectrometer Test Pattern test. 2. QLA analysis shows that phot/spec test patterns are the same as the reference phot/spec test patterns.

Test Procedure:

Step#	Action	Comments
1	Annotate the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
2	Run QLA script FUNC-DCU-03.py on QLA console.	
3	Run FUNC-DCU-03 test procedure from the HCSS Test Procedure window on TOPE	
4	Annotate the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-03	**DCUFRAMECNT**	**1400/2100**			

Start time @:
End time @:
OBSID:
Commets:

3.3.25 FUNC-DCU-04P

Test Id:	FUNC-DCU-04P
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Photometer LIAs ON
Success Criteria:	Test passed if : 1. SCUDCDCSTAT parameter goes from 4 to 5. 2. Photometer LIA card voltages are showing correct readings of +5V,+9V,-9V. 3. Photometer LIA temperatures show an increase indicating that they are ON.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the HK parameters: PLIAP5V PLIAP9V PLIAM9V LIAP1/2/3/4/5/6/7/8/9TEMP	
2	Run FUNC-DCU-04P test procedure from the HCSS Test Procedure window on TOPE	
5	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-04P	**SCUDCDCSTAT** **PLIAP5V** **PLIAP9V** **PLIAM9V** **LIA1/2/3/4/5/6/7/9TEMP**	**4/5** **0/~ +5V** **0/~+9V** **0/~-9V** **N/A/ [290-300]K**			

Start time @:
End time @:
OBSID:
Commets:

3.3.26 FUNC-DCU-05P

Test Id:	FUNC-DCU-05P
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON
Success Criteria:	Test passed if : 1. The first channel of the 32 on each photometer LIA card (16 bit word in the photometer offset packet) shows the commanded offset variation 0x1,0x3,0x6,0x9,0xc,0xf

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the Photometer Offset Frame parameters: PHOTOFF001 PHOTOFF033 PHOTOFF055 PHOTOFF087 PHOTOFF119 PHOTOFF151 PHOTOFF183 PHOTOFF215 PHOTOFF247 PHOTOFF279	
2	Run FUNC-DCU-05P test procedure from the HCSS Test Procedure window on TOPE	
5	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-05P					

Start time @:
End time @:
OBSID:
Commets:

3.3.27 FUNC-DCU-11P

Test Id:	FUNC-DCU-11P
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON + Photometer BIAS ON +Photometer JFETs ON
Success Criteria:	Test passed if Photometer JFET source and drain voltages are correct: 1. PSWJFETVSS1/2/3/4/5/6 (RAW: 0x4C CONVERTED ~ -1.5V). 2. PMLWJFETVSS1/2/3/4 (RAW: 0x4C CONVERTED ~ -1.5V). 3. PSWJFETSTAT = 0x3F 4. PMLWJFETSTAT = 0x1F

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-11P test procedure from the HCSS Test Procedure window on TOPE	
2	After the test Annotate the values RAW and converted values of: PSWJFETSTAT,PMLWJFETSTAT, PSWJFET1/2/3/4/5/6V PMWJFET1/2/3/4V PLWJFET1/2V located in DCU PARAMETERS AND	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-11P	**PSWJFETSTAT** **PMLWJFETSTAT** **PSWJFET1/2/3/4/5/6V** **PMWJFET1/2/3/4V** **PLWJFET1/2V**	**0/0x3f** **0/0x1f** **0V/-1.5V** **0V/-1.5V** **0V/-1.5V**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.28 FUNC-DCU-13P

Test Id:	FUNC-DCU-13P
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON + Photometer BIAS ON +Photometer JFETs ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON + Photometer BIAS ON +Photometer JFETs ON
Success Criteria:	Test passed if : The photometer detectors show a small linear variation on the output voltage when different bias is applied through the load curve.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of a couple of pixels on each of the photometer BDAs	
2	Run FUNC-DCU-13P test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat step 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-13P				**N/A**	

Start time @:
End time @:
OBSID:
Commets:

Step#	Action	Comments
1	From TOPE HCSS Test Procedures run **PDET-OFF**	

3.3.29 FUNC-DCU-04S

Test Id:	FUNC-DCU-04S
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON
Success Criteria:	Test passed if : 1. SCUDCDCSTAT parameter goes from 4 to 6. 2. Spectrometer LIA card voltages are showing correct readings of +5V,+9V,-9V. 3. Spectrometer LIA temperatures show an increase indicating that they are ON.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the HK parameters: SLIAP5V SLIAP9V SLIAM9V LIAS1/2/3TEMP	
2	Run FUNC-DCU-04S test procedure from the HCSS Test Procedure window on TOPE	
5	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-04S	**SCUDCDCSTAT** **SLIAP5V** **SLIAP9V** **SLIAM9V** **LIA1/2/3TEMP**	**4/6** **0/~ +5V** **0/~+9V** **0/~-9V** **N/A/ [290-300]K**			

Start time @:
End time @:
OBSID:
Commets:

3.3.30 FUNC-DCU-05S

Test Id:	FUNC-DCU-05S
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON
Success Criteria:	Test passed if : 1. The first channel of the 12 on each spectrometer LIA card (16 bit word in the photometer offset packet) shows the commanded offset variation 0x1,0x3,0x6,0x9,0xc,0xf

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the Photometer Offset Frame parameters: SPECOFF01 SPECOFF13 SPECOFF25 SPECOFF37 SPECOFF49 SPECOFF61	
2	Run FUNC-DCU-05S test procedure from the HCSS Test Procedure window on TOPE	
5	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-05S					

Start time @:
End time @:
OBSID:
Commets:

3.3.31 FUNC-DCU-11S

Test Id:	FUNC-DCU-11S
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Success Criteria:	Test passed if SCUDCDCSTAT goes from 4 to 6, Spectrometer LIAs voltages are correct and SJFET voltages are also correct.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-11S test procedure from the HCSS Test Procedure window on TOPE	
2	After the test Annotate the values RAW and converted values of: LIASTAT SLIAP5V, SLIAP9V, SLIAN9V, SSWJFETSTAT,SLWJFETSTAT, SSWJFET1V,SLWJFET2V located in DCU PARAMETERS AND	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-11S	**SCUDCDCSTAT** **LIASTAT** **SLIAP5V** **SLIAP9V** **SLIAN9V** **SSWJFETSTAT** **SLWJFETSTAT** **SSWJFET1/2V** **SLWJFET1/2V**	**4/6** **0/0** **0V/ ~ 5V** **0V/~11V** **0V/-11V** **0/0x3f** **0/0x3f** **0V/-1.5V** **0V/-1.5V**		**N/A**	

Start time @:
End time @:
OBSID:
Commets:

3.3.32 FUNC-DCU-13S

Test Id:	FUNC-DCU-13S
Initial Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Final Configuration:	**DRCU_ON** + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Success Criteria:	Test passed if : The spectrometer detectors show a small linear variation on the output voltage when different bias is applied through the load curve.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-13S test procedure from the HCSS Test Procedure window on TOPE	
2	Contingency: If test fails repeat step 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-13S				**N/A**	

Start time @:
End time @:
OBSID:
Commets:

Step#	Action	Comments
1	From TOPE HCSS Test Procedures run **SDET-OFF**	

4. END TEST SEQUENCE

4.1 NORMAL END TEST SEQUENCE

The following table shows the necessary steps to be followed to end the warm functional test sequence.

Step#	Action	HK parameters	Expected Value	Comments	Check
1	Check BSM is OFF	CHOPSENSPWR JIGGSENSPWR	0 0		
2	Check SMEC is OFF	SMECENCPWR	0		
3	Run MCU-OFF from the HCSS Test Procedure window on TOPE	SCUDCDCSTAT	0		
4	Check Instrument Configuration	MODE	0x100/ DRCU_ON		
5*	Run SCU_OFF from the HCSS Test Procedure window on TOPE	SCUDCDCSTAT SUBKSTAT	0 0		
6*	Run DRCU_OFF from the HCSS Test Procedure window on TOPE	MODE	0/ DPU_ON		

* These two steps should ONLY be executed if the functional test takes place BEFORE the instrument is placed in the test cryostat. If the instrument is already in the cryostat and the cryo-harness are connected this steps should NOT be executed.

FINAL INSTRUMENT CONFIGURATION IN THE CASE STEPS 1 to 4 are executed is DRCU_ON
FINAL INSTRUMENT CONFIGURATION IN THE CASE STEPS 1 to 6 are executed is DPU_ON

4.2 END TEST SEQUENCE WHEN THE FUNCTIONAL TEST HAS FAILED

The following table shows the necessary steps to be followed to end the warm functional test sequence when this has been declared failed.

Step#	Action	HK parameters	Expected Value	Comments	Check
1	Check BSM is OFF	CHOPSENSPWR JIGGSENSPWR	0 0		
2	Check SMEC is OFF	SMECENCPWR	0		
3	Run MCU-OFF from the HCSS Test Procedure window on TOPE	SCUDCDCSTAT	0		

4	**Check Instrument Configuration**	**MODE**	**0x100/ DRCU_ON**		
5	**Run SCU_OFF from the HCSS Test Procedure window on TOPE**	**SCUDCDCSTAT SUBKSTAT**	**0 0**		
6	**Run DRCU_OFF from the HCSS Test Procedure window on TOPE**	**MODE**	**0/ DPU_ON**		

FINAL INSTRUMENT CONFIGURATION IN THE CASE STEPS DPU_ON

5. ANNEXE1 (INSTRUMENT NOMINAL CONFIGURATION/MODES)

	OFF	INIT	DPU_ON	DRCU_ON	REDY	PHOT STBY	SPEC STBY	CREC	SAFE
DPU		**ON**	**ON**	**ON**	**ON**	**ON**	**ON**	**ON**	**ON**
Essential Hsk packets			0.5Hz	0.5Hz	0.5Hz	0.5Hz	0.5Hz	0.5Hz	0.5Hz
Normal Hsk packets			1.0Hz	1.0Hz	0.25Hz	0.25Hz	0.25Hz	1.0Hz	0.25Hz
TC Acceptance		TBC	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Event packets		Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Science packets									
VM								Cooler_Recycle	
VM1						Det_Temp_Ctrl			
VM2									
VM3									
MODE			0x0000	0x0100	0x0200	0x0300	0x0400	0x0600	0x0900
DRCU			**ON**	**ON**	**ON**	**ON**	**ON**	**ON**	
SCU									
Temp Channels powered					Yes	Yes	Yes	Yes	
SubK Channel powered					Yes	Yes	Yes	Yes	
PCAL source powered									
SCAL sources powered							TBD		
TC Heater powered						Yes			
Cooler SP Heater powered								Yes	
Cooler EV HS powered								Yes	
Cooler SP HS powered					Yes	Yes	Yes	Yes	
DCU									
Photometer BIAS						Yes			
Photometer JFETS						Yes			
Photometer LIAs						Yes			
TC BIAS						Yes			
TC JFETS						Yes			
TC LIAs						Yes			
Spectrometer BIAS							Yes		
Spectrometer JFETS							Yes		
Spectrometer LIAs							Yes		
MCU									

DSP					On	On	On	On	
BSM						Hold	Hold		
SMEC							Hold		